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Shu-Sheng Zhang, Li-Li Xu, Sai Bi, Xue-Mei Li and Yong-Hong Wen*

College of Chemistry and Molecular Engineering, Qingdao University of Science and Technology, 266042 Qingdao, Shandong, People's Republic of China

Correspondence e-mail: shushzhang@126.com

Key indicators

Single-crystal X-ray study T = 294 K Mean σ (C–C) = 0.004 Å R factor = 0.057 wR factor = 0.157 Data-to-parameter ratio = 13.9

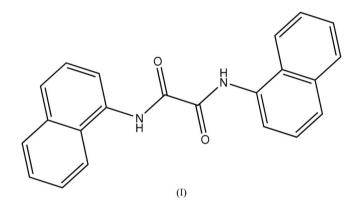
For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

N,N'-Di-1-naphthyloxamide

The molecule of the title compound, $C_{22}H_{16}N_2O_2$, lies on a crystallographically imposed center of symmetry at the midpoint of the C–C bond of the oxamide unit. In the crystal structure, intermolecular C–H···O and N–H···O hydrogen bonds link the molecules into ribbons along the *c* axis. The packing is further stabilized by C–H··· π interactions.

Comment

In our ongoing studies of oxamide derivatives, the title compound, (I), was obtained. We report here its synthesis and crystal structure.



In the molecule of the title compound, (I) (Fig. 1), the bond lengths and angles are within normal ranges (Allen *et al.*, 1987). It has a crystallographically imposed center of symmetry at the mid-point of the C11-C11ⁱ bond [symmetry code: (i) -x, 2 - y, 1 - z] and an intramolecular C9-H9A···O1 hydrogen bond (Table 1) forms a six-membered ring.

The dihedral angle between the two benzene rings is 2.17 (4)°. The naphthalene ring system and the O1/N1/C10/C11/O1ⁱ/N1ⁱ/C10ⁱ/C11ⁱ unit [symmetry code: (i) -x, 2 - y, 1 - z] are each nearly planar, having total puckering amplitudes, $Q_{\rm T}$, of 0.0614 (3) and 0.0589 (4) Å, respectively (Cremer & Pople, 1975); the dihedral angle between them is 40.9 (1)°.

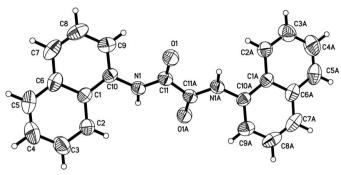
As can be seen from the packing diagram (Fig. 2), intermolecular C-H···O and N-H···O hydrogen bonds (Table 1) link the molecules into ribbons along the *c* axis. The packing is further stabilized by C-H··· π interactions.

Experimental

To a solution of 1-naphthylamine (28.6 g, 0.2 mol) in benzene (70 ml) was added dropwise a solution of oxalyl chloride (6.4 g, 0.05 mol) in benzene (30 ml), and the mixture was stirred at 343 K for 6 h. After

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The molecular structure of (I), showing 50% probability displacement ellipsoids and the atom-numbering scheme. The suffix A corresponds to symmetry code (-x, 2 - y, 1 - z).

cooling to room temperature, 50 ml of water was added to the reaction mixture and the organic phase was washed three times with water to give a solid. The title compound was obtained after drying the solid at room temperature for 3 d. Colorless single crystals suitable for X-ray diffraction study were obtained by slow evaporation of a dimethylformamide solution over a period of 5 d.

Z = 2

 $D_x = 1.339 \text{ Mg m}^{-3}$ Mo K α radiation $\mu = 0.09 \text{ mm}^{-1}$ T = 294 (2) K Block, colorless $0.41 \times 0.25 \times 0.07 \text{ mm}$

4238 measured reflections

 $R_{\rm int}=0.045$

 $\theta_{\rm max} = 26.0^\circ$

1643 independent reflections 993 reflections with $I > 2\sigma(I)$

Crystal data

$C_{22}H_{16}N_2O_2$
$M_r = 340.37$
Monoclinic, $P2_1/c$
a = 14.351 (5) Å
b = 6.105 (2) Å
c = 9.639 (4) Å
$\beta = 91.798 \ (6)^{\circ}$
V = 844.1 (5) Å ³

Data collection

Siemens SMART 1000 CCD areadetector diffractometer ω scans Absorption correction: multi-scan

(SADABS; Sheldrick, 1996) $T_{min} = 0.965, T_{max} = 0.994$

Refinement

Refinement on F^2	$w = 1/[\sigma^2(F_o^2) + (0.0713P)^2]$
$R[F^2 > 2\sigma(F^2)] = 0.057$	+ 0.0595P]
$wR(F^2) = 0.157$	where $P = (F_0^2 + 2F_c^2)/3$
S = 1.04	$(\Delta/\sigma)_{\rm max} < 0.001$
1643 reflections	$\Delta \rho_{\rm max} = 0.15 \text{ e } \text{\AA}^{-3}$
118 parameters	$\Delta \rho_{\rm min} = -0.18 \text{ e} \text{ \AA}^{-3}$
H-atom parameters constrained	

Table 1

Hydrogen-bond geometry (Å, °).

Cg1 and Cg2 are the centroids of atoms C1-C6 and C1/C6-C10, respectively.

$D - H \cdots A$	D-H	$H \cdot \cdot \cdot A$	$D \cdots A$	$D - \mathbf{H} \cdots A$
$C2-H2A\cdots Cg2^{ii}$	0.93	2.97	3.548	122
$C7-H7A\cdots Cg1^{iii}$	0.93	3.18	3.836	129
$N1 - H1A \cdots O1^{i}$	0.86	2.30	2.700 (3)	108
$N1-H1A\cdotsO1^{iv}$	0.86	2.54	3.116 (3)	125
C9−H9A···O1	0.93	2.52	2.954 (3)	109
$C9-H9A\cdotsO1^{v}$	0.93	2.49	3.272 (4)	141

Symmetry codes: (i) -x, -y + 2, -z + 1; (ii) $x, -y + \frac{1}{2}, z - \frac{3}{2}$; (iii) $x, -y - \frac{1}{2}, z - \frac{1}{2}$; (iv) $x, -y + \frac{3}{2}, z - \frac{1}{2}$; (v) $-x, y - \frac{1}{2}, -z + \frac{3}{2}$.

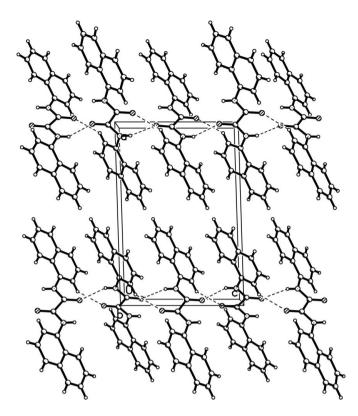


Figure 2
Packing diagram of (I). Hydrogen bonds are shown as dashed lines.

All H atoms were located in difference Fourier maps and constrained to ride on their parent atoms, with N-H = 0.86 Å (for NH) and C-H = 0.93 Å for aromatic H atoms, and with $U_{iso}(H) = 1.2 U_{eq}(C,N)$.

Data collection: *SMART* (Siemens, 1996); cell refinement: *SAINT* (Siemens, 1996); data reduction: *SAINT*; program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL* (Siemens, 1996); software used to prepare material for publication: *SHELXTL*, *PARST* (Nardelli, 1995) and *PLATON* (Spek, 2003).

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